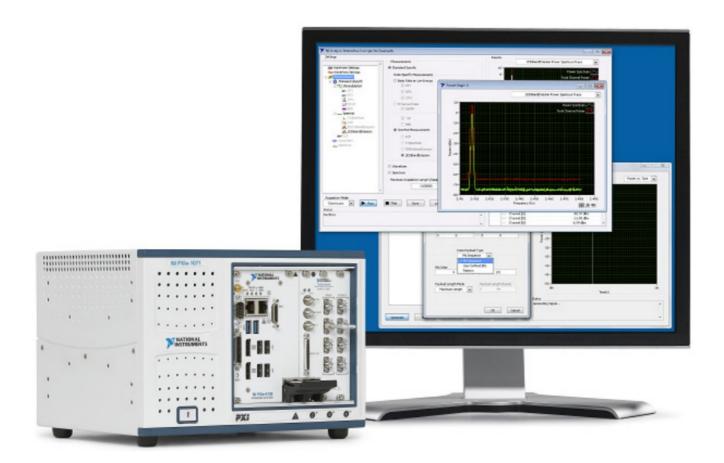


# **APEX WAVES PXIe-5646 Bluetooth Test Toolkit User Manual**

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## **APEX WAVES PXIe-5646 Bluetooth Test Toolkit**



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#### **COMPREHENSIVE SERVICES**

We offer competitive repair and calibration services, as well as easily accessible documentation and free downloadable resources.

#### **SELL YOUR SURPLUS**

We buy new, used decommissioned, and surplus parts from every Ni series. We work out the best solution to suit your individual needs.

- · Sell For Cash
- · Get Credit
- Receive a Trade-In Deal

**Bridging the gap** between manufacturer and you legacy test system,.

#### **OBSOLETE NI HARDWARE IN STOCK \$ READY TO SHIP**

We stock New, New Surplus, Refurbished, and Reconditioned NI Hardware.

#### **Learn more about Bluetooth Test Toolkit**

- Generate and analyze Bluetooth: 1.x, 2.x+EDR, 3.x+HS, 4.2, LE, and 5.0 LE (2 Mbps data rate)
- Characterize performance of Bluetooth design with easy-to-use soft front panels
- Automate Bluetooth measurements with comprehensive LabVIEW and C APIs
- Integrate with PXI Vector Signal Transceiver (VST), or separate PXI Vector Signal Generators (VSGs) and PXI Vector Signal Analyzers (VSAs)

#### **Built for Bluetooth Characterization Test and Measurement**

The Bluetooth Test Toolkit gives you direct and fine control over the generation and analysis of Bluetooth

waveforms with industry-leading speed and accuracy. Use the Bluetooth Test Toolkit to characterize a variety of Bluetooth connectivity products, such as RF front end components, wireless modules, and end-user devices.

The Bluetooth Test Toolkit gives you the flexibility to control your measurement system manually with the toolkit's generation and analysis soft front panels, as well as to automate your bench with an extensive system design software API for LabVIEW, C, or .NET. You will benefit from a large collection of available example code when programming and automating your Bluetooth measurement systems.

Characterize your device with the toolkit's comprehensive support for the latest features of the Bluetooth standard, including Low-Energy, extended payload, and long-range packets that are part of the Bluetooth 5.0 standard.

## **Key Features**

#### Bluetooth Classic, Low-Energy, and Direct Test Mode

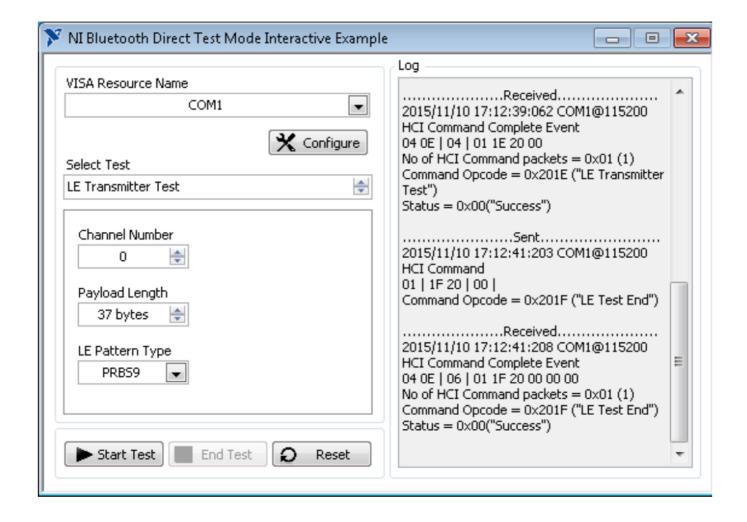
The Bluetooth standard now defines specific Bluetooth Low-Energy (BLE) RF PHY Test Cases and a new Direct Test Mode (DTM) for DUT control to make sure that Bluetooth Low-Energy devices from all manufacturers operate properly. This standardization also verifies that a basic level of system performance is guaranteed for all BLE products. With both DTM and a more relaxed RF PHY specification for Bluetooth Low-Energy, fewer PHY test cases and optimized test case implementations contribute to much shorter BLE RF PHY test times.

The NI Bluetooth Test Toolkit supports these BLE measurements and the new packet types associated with them, such as:

- LE Packet
- LE Extended payload packet (255 bytes)
- LE-Enhanced (1 and 2 Mbps)
- LE-Long range (125 and 500 kbps)

Additionally, the toolkit ships with a Direct Test Mode Interactive Example to help you control and test BLE DUTs easily.

Figure 1. Direct test mode interactive example



## **Fast and Accurate Measurements**

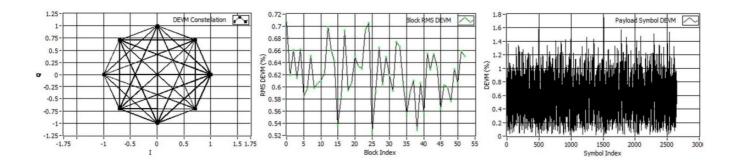
Combine the Bluetooth Test Toolkit with a VST to achieve industry-leading modulation and spectral measurements; the average time for a DEVM measurement is less than 33 ms.

#### Modulation

Table 1. Mean Block EVM in loopback using a VST

| Tx Power Level | Mean Block RMS EVM (%) | Mean Block RMS Magnitude Error (%) |
|----------------|------------------------|------------------------------------|
| 0              | 0.59                   | 0.41                               |
| -5             | 0.56                   | 0.40                               |
| -10            | 0.54                   | 0.38                               |
| -15            | 0.52                   | 0.36                               |

Figure 2. Constellation plot of a 3-DH5 signal; RMS DEVM measurement; payload symbol DEVM (%)

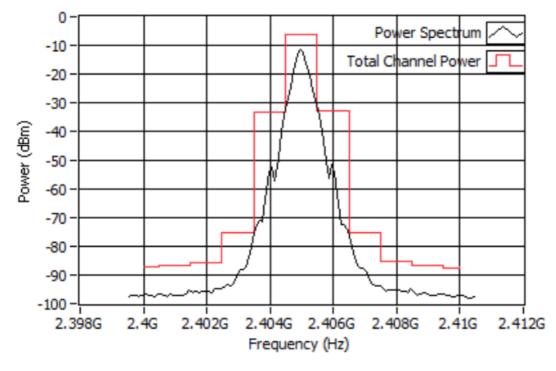


## **Spectral**

Table 2. Spectrum measurement speeds using the NI Bluetooth Suite and the VST

| Type of Measurement   | Value              | Measurement T ime |
|---|--------------------|-------------------|
| ACP (79 channels 3-DH5 packet type -25 dBm main ch power)   | -79 dBm            | < 330 ms          |
| ACP (10 channels, 3-DH5 packet type, -25 dBm main ch power) | -79 dBm            | < 170 ms          |
| DF1 (DM1 packet type)                                       | Df1avg = 80.87 KHz | < 8 ms            |
| -15   | 0.52               | 0.36              |

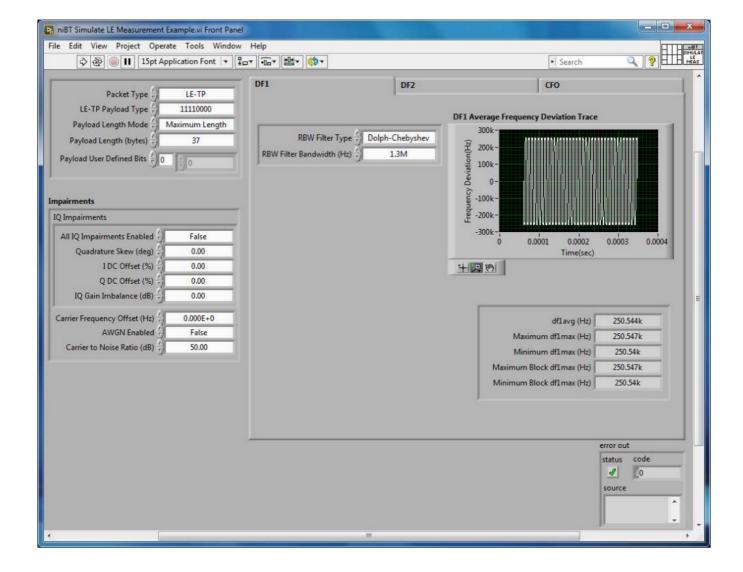
Figure 3. Tx output power spectrum measurement



#### **Simulation**

The Bluetooth Test Toolkit enables you to simulate and manipulate Bluetooth signals. You can also inject various impairments to characterize effects on the resulting signal measurements.

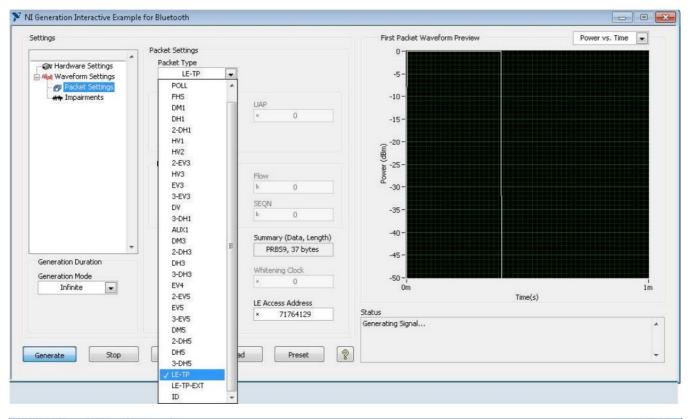
Figure 4. Code to simulate the effects of hardware impairments on the BT signal

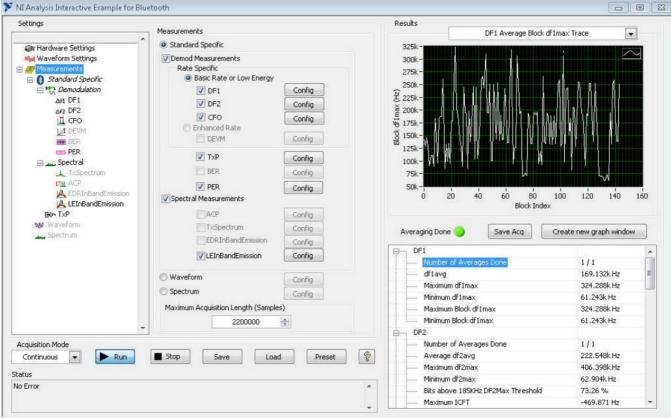


## **Soft Front Panel**

Use soft front panels (SFPs) to generate and analyze Bluetooth signals, define custom payloads, and inject signal impairments such as noise, IQ imbalance, skew, and DC offset. Furthermore, the SFPs allow you to save waveforms and measurements for either later modulation and spectral analysis or for loading equivalent settings into the programmable API.

Figure 5. Bluetooth generation and analysis soft front panels

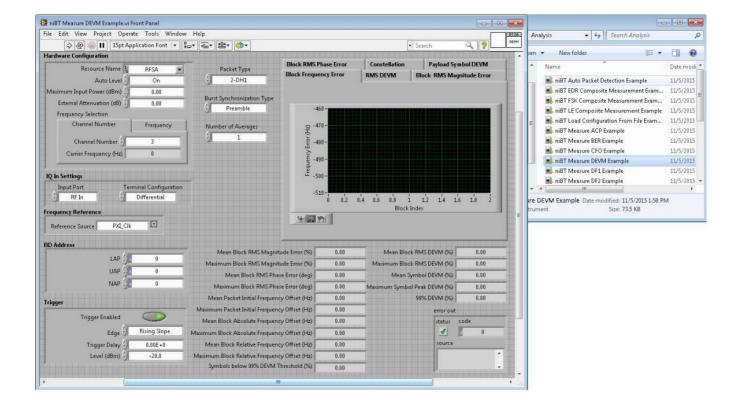




# **Application Programming Interface (API)**

The Bluetooth Test Toolkit includes an API for LabVIEW, C, and .NET, with which you can create custom code for all kinds of test scenarios or custom settings. The API gives you fine control over the Bluetooth packets and it includes an extensive library of example code to get you started quickly on the many different Bluetooth measurements for the various types of packets, including Bluetooth Low Energy.

Figure 6. Example of a custom LabVIEW front panel for waveform analysis



## **Supported Hardware**

The Bluetooth Test Toolkit is compatible with several RF VSTs and certain VSAs, so you can choose a device based on the specific needs of your application.

Table 3. NI hardware compatible with the Bluetooth Toolkit

| Instrument                                      | Real-Time Bandwidth |  |
|---|---------------------|--|
| PXIe-5644 VST                                   | Up to 80 MHz        |  |
| PXIe-5645 VST with Baseband IQ Input and Output | Up to 80 MHz        |  |
| PXIe-5646 VST                                   | Up to 200 MHz       |  |
| PXIe-5840 VST                                   | Up to 1 GHz         |  |
| PXIe-5668 VSA                                   | Up to 765 MHz       |  |

# **Supported Measurements**

#### **Transmit Power**

- Total Average Power
- · Access Code and Header Average Power
- · Payload Relative Power
- Maximum Average Power
- · Minimum Average Power
- Payload Average Power

#### **Demodulation Measurements**

DF1 Average Block df1max DF1 Average Frequency

Deviation Trace

DF2 Average Block df2max Trace

DF2 Average Frequency

Deviation Trace Max ICFT

Max Carrier Drift
Max Carrier Drift/50us

Bits above 185kHz DF2Max

Threshold (%)

Max Payload Block Frequency Offs

Max Carrier Drift / 55us

DF2 Block Frequency Offset Trace DF2 Maximum Block df2max Trace

DF2 Minimum Block df2max Trace

CFO Block Frequency Offset

CFO Payload Frequency Deviation

Max ICFT
Max Carrier Drift

Max Carrier Drift / 50us

Max Payload Block Frequency Offs

et (Hz)

Max Carrier Drift / 55us

#### **DEVM**

deg)

Mean Block RMS DEVM (%)
Maximum Block RMS DEVM (%)
Mean Symbol DEVM (%)
Maximum Symbol DEVM (%) 99%
DEVM (%)
Mean Block RMS Magnitude Error (%)
Maximum Block RMS Magnitude Error (%)
Mean Block RMS Phase Error (deg )

Maximum Block RMS Phase Error (

Mean Packet Initial Frequency Offs et (Hz)

Maximum Packet Initial Frequency Offset (Hz)

Mean Block Absolute Frequency Of fset (Hz)

Maximum Block Absolute Frequency Offset (Hz)

Mean Block Relative Frequency Off set (Hz)

Maximum Block Relative Frequency Offset (Hz)

Symbols below 99% DEVM Thresh old (%)

Impairments: IQ Gain Imbalance (d

Impairments: Quadrature Skew (de

Impairments: I DC Offset (%)

Impairments: Q DC Offset (%) BER

(%)

Sample Population Used FER % Number of Frames Used

#### Spectral Measurements

Peak Power TxP Average Power versus Time Bandwidth TxSpectrum ACP

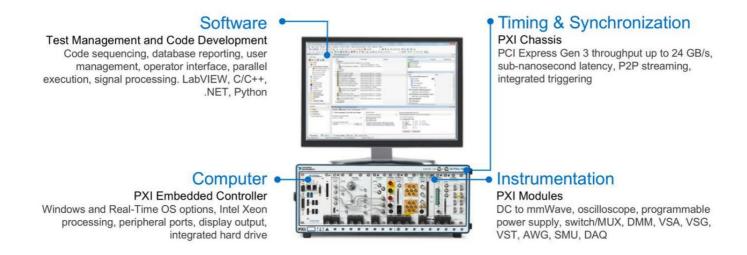
EDRInBandEmission LEInBandEmission Raw IQ Data Waveform Spectrum

#### Platform-Based Approach to Test and Measurement

#### What Is PXI?

Powered by software, PXI is a rugged PC-based platform for measurement and automation systems. PXI combines PCI electrical-bus features with the modular, Eurocard packaging of Compact PCI and then adds specialized synchronization buses and key software features. PXI is both a high-performance and low-cost deployment platform for applications such as manufacturing test, military and aerospace, machine monitoring, automotive, and industrial test. Developed in 1997 and launched in 1998, PXI is an open industry standard governed by the PXI Systems Alliance (PXISA), a group of more than 70 companies chartered to promote the PXI

standard, ensure interoperability, and maintain the PXI specification.



#### **Integrating the Latest Commercial Technology**

By leveraging the latest commercial technology for our products, we can continually deliver high performance and high quality products to our users at a competitive price. The latest PCI Express Gen 3 switches deliver higher data throughput, the latest Intel multicore processors facilitate faster and more efficient parallel (multisite) testing, the latest FPGAs from Xilinx help to push signal processing algorithms to the edge to accelerate measurements, and the latest data converters from TI and ADI continually increase the measurement range and performance of our instrumentation.



#### **PXI** Instrumentation

NI offers more than 600 different PXI modules ranging from DC to mmWave. Because PXI is an open industry standard, nearly 1,500 products are available from more than 70 different instrument vendors. With standard processing and control functions designated to a controller, PXI instruments need to contain only the actual instrumentation circuitry, which provides effective performance in a small footprint. Combined with a chassis and controller, PXI systems feature high-throughput data movement using PCI Express bus interfaces and subnanosecond synchronization with integrated timing and triggering.

# Oscilloscopes

Sample at speeds up to 12.5 GS/s with 5 GHz of analog bandwidth, featuring numerous triggering modes and deep onboard memory.



# • <u>Digital Instruments</u>

Perform characterization and production test of semiconductor devices with timing sets and per channel pin parametric measurement unit (PPMU)



# • Frequency Counters

Perform counter timer tasks such as event counting and encoder position, period, pulse, and frequency measurements.



# • Power Supplies & Loads

Supply programmable DC power, with some modules including isolated channels, output disconnect functionality, and remote sense.



# • Switches (Matrix & MUX)

Feature a variety of relay types and row/column configurations to simplify wiring in automated test systems.



# • GPIB, Serial, & Ethernet

Integrate non-PXI instruments into a PXI system through various instrument control interfaces.



# • **Digital Multimeters**

Perform voltage (up to 1000 V), current (up to 3A), resistance, inductance, capacitance, and frequency/period measurements, as well as diode tests.



## • Waveform Generators

Generate standard functions including sine, square, triangle, and ramp as well as user-defined, arbitrary waveforms.



## • Source Measure Units

Combine high-precision source and measure capability with high channel density, deterministic hardware sequencing, and Source Adapt transient optimization.



# • FlexRIO Custom Instruments & Processing

Provide high-performance I/O and powerful FPGAs for applications that require more than standard instruments can offer.



# • <u>Vector Signal Transceivers</u>

Combine a vector signal generator and vector signal analyzer with FPGA-based, real-time signal processing and control.



# • Data Acquisition Modules

Provide a mix of analog I/O, digital I/O, counter/timer, and trigger functionality for measuring electrical or physical phenomena.



# **Hardware Services**

All NI hardware includes a one-year warranty for basic repair coverage, and calibration in adherence to NI specifications prior to shipment. PXI Systems also include basic assembly and a functional test. NI offers

additional entitlements to improve uptime and lower maintenance costs with service programs for hardware. Learn more at <a href="ni.com/services/hardware">ni.com/services/hardware</a>.

|  | Standard     | Premium      | Description  |
|--|--------------|--------------|--|
| Program Duration                                   | 3 or 5 years | 3 or 5 years | Length of service program  |
| Extended Repair C overage                          | •            | •            | NI restores your device's functionality and includes firmware updates and factory calibration.                                 |
| System Configurati<br>on, Assembly, and<br>Test1   | •            | •            | NI technicians assemble, install software in, and test your sy stem per your custom configuration prior to shipment.           |
| Advanced Replace ment2                             |              | •            | NI stocks replacement hardware that can be shipped immed iately if a repair is needed.   |
| System Return Mat<br>erial Authorization<br>(RMA)1 |              | •            | NI accepts the delivery of fully assembled systems when per forming repair services.   |
| Calibration Plan (O ptional)                       | Standard     | Expedited3   | NI performs the requested level of calibration at the specified calibration interval for the duration of the service pr ogram. |

- 1. This option is only available for PXI, CompactRIO, and CompactDAQ systems.
- 2. This option is not available for all products in all countries. Contact your local NI sales engineer to confirm availability.
- 3. Expedited calibration only includes traceable levels.

## **PremiumPlus Service Program**

NI can customize the offerings listed above, or offer additional entitlements such as on-site calibration, custom sparing, and life-cycle services through a PremiumPlus Service Program. Contact your NI sales representative to learn more.

#### **Technical Support**

Every NI system includes a 30-day trial for phone and e-mail support from NI engineers, which can be extended through a <u>Software Service Program (SSP)</u> membership. NI has more than 400 support engineers available around the globe to provide local support in more than 30 languages. Additionally, take advantage of NI's award winning <u>online resources</u> and <u>communities</u>.

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18 August 2017

## **Customer Support**

## Have a question? Contact Us



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#### **Documents / Resources**



APEX WAVES PXIe-5646 Bluetooth Test Toolkit [pdf] User Manual PXIe-5646 Bluetooth Test Toolkit, PXIe-5646, Bluetooth Test Toolkit, Toolkit

#### References

- <u>Ingineer Ambitiously NI</u>
- Product Documentation NI
- M Hardware Services NI
- M RFmx for Bluetooth® Test NI
- M Engineer Ambitiously NI
- NI Community National Instruments
- M Contact Us NI
- What Are PXI Digital Pattern Instruments? NI
- What Are PXI Digital Multimeters? NI
- M What Are PXI Oscilloscopes? NI
- Mat Are PXI Source Measure Units? NI
- M What Are PXI Switches? NI
- M FlexRIO Custom Instruments and Processing Electronic Test and Instrumentation NI
- Trequency Counters Electronic Test and Instrumentation NI
- M GPIB, Serial, and Ethernet Electronic Test and Instrumentation NI
- Multifunction I/O Data Acquisition and Control NI
- Power Supplies and Loads Electronic Test and Instrumentation NI
- Maveform Generators Electronic Test and Instrumentation NI

- Mhat Is a PXI Vector Signal Transceiver? NI
- <u>Product Documentation NI</u>
- M Hardware Services NI
- NI Software Services NI
- NI Support NI
- NV PXIe-5646 National Instruments PXI Vector Signal Transceiver | Apex Waves

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